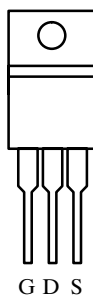


N-Channel Enhancement-Mode Transistor, Logic Level

Product Summary

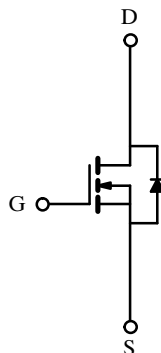
$V_{(BR)DSS}$ (V)	$r_{DS(on)}$ (Ω)	I_D (A)
30	0.01	60

TO-220AB



Top View

DRAIN connected to TAB



N-Channel MOSFET

Absolute Maximum Ratings ($T_C = 25^\circ\text{C}$ Unless Otherwise Noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V_{DS}	30	V
Gate-Source Voltage	V_{GS}	± 20	
Continuous Drain Current	I_D	$T_C = 25^\circ\text{C}$	A
		$T_C = 100^\circ\text{C}$	
Pulsed Drain Current	I_{DM}	240	mJ
Avalanche Current	I_{AR}	60	
Avalanche Energy	E_{AS}	180	
Repetitive Avalanche Energy ^a	E_{AR}	90	W
Power Dissipation	P_D	$T_C = 25^\circ\text{C}$	
		$T_C = 100^\circ\text{C}$	
Operating Junction and Storage Temperature Range	T_J, T_{stg}	-55 to 150	$^\circ\text{C}$
Lead Temperature ($1/16''$ from case for 10 sec.)	T_L	300	

Thermal Resistance Ratings

Parameter	Symbol	Typical	Maximum	Unit
Junction-to-Ambient	R_{thJA}		80	$^\circ\text{C}/\text{W}$
Junction-to-Case	R_{thJC}		1.2	
Case-to-Sink	R_{thCS}	1.0		

Notes:

a. Duty cycle $\leq 1\%$

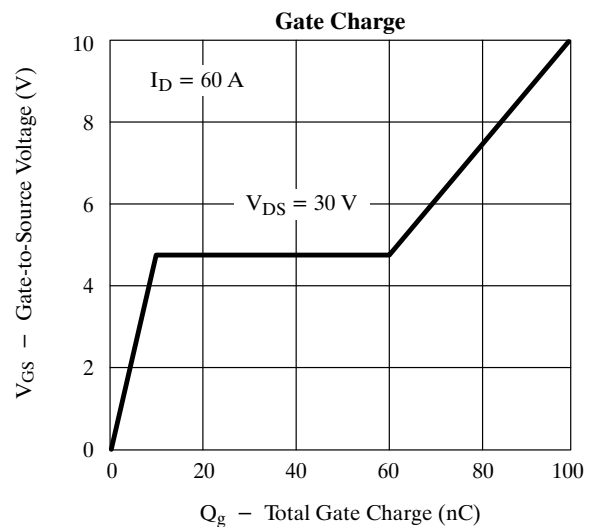
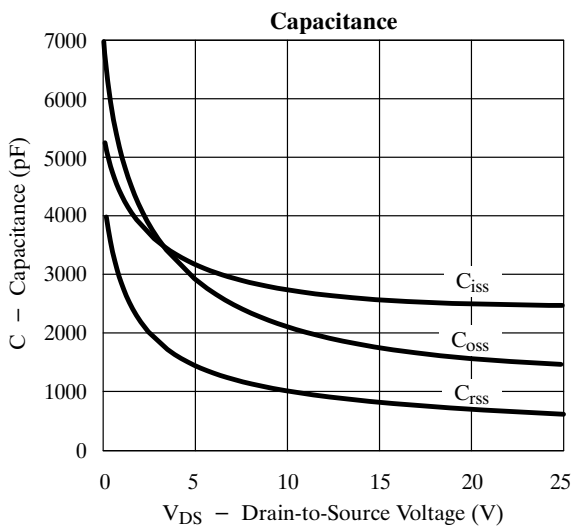
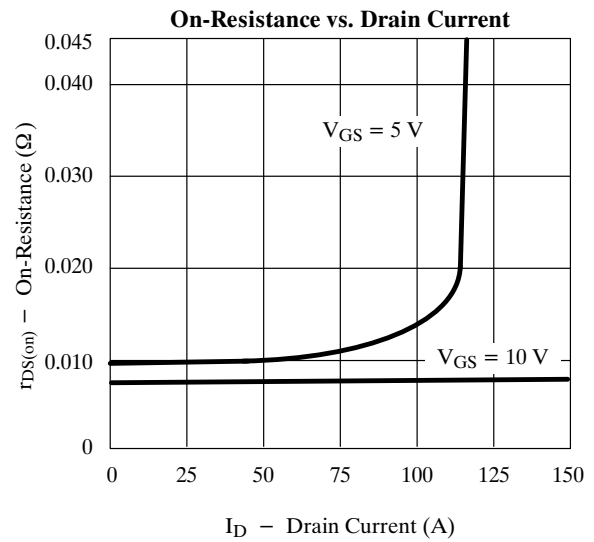
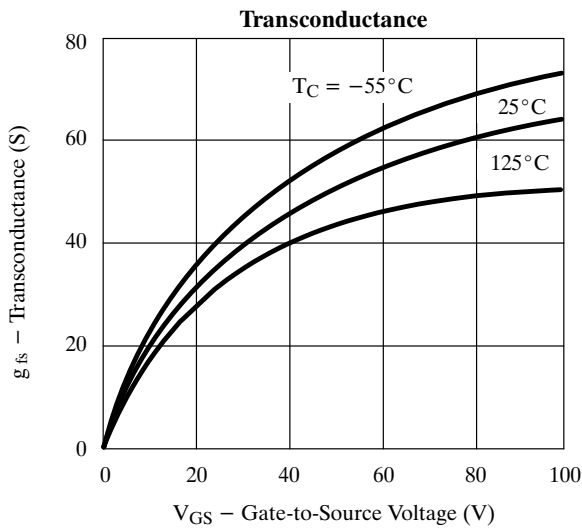
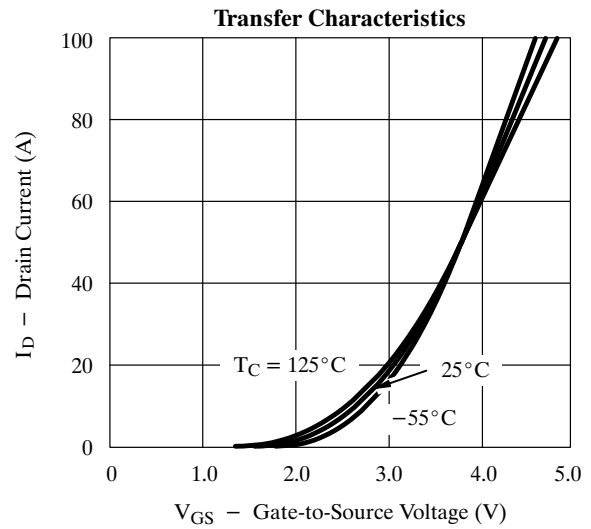
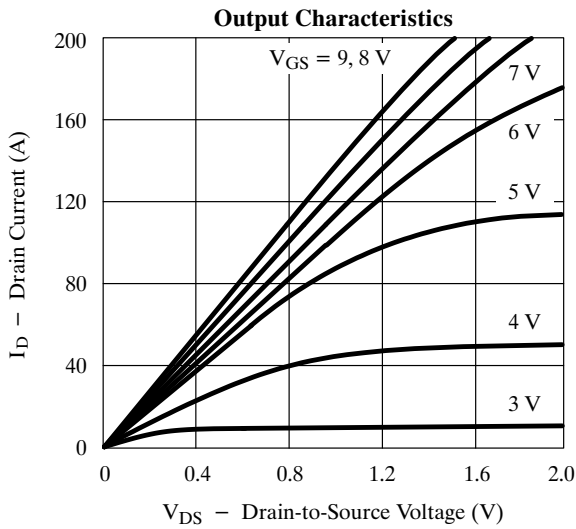
Specifications ($T_J = 25^\circ\text{C}$ Unless Otherwise Noted)

Parameter	Symbol	Test Condition	Min	Typ ^a	Max	Unit
Static						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0\text{ V}, I_D = 250\ \mu\text{A}$	30			V
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 1\ \text{mA}$	0.8		3.0	
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0\ \text{V}, V_{GS} = \pm 20\ \text{V}$			± 500	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 24\ \text{V}, V_{GS} = 0\ \text{V}$			25	μA
		$V_{DS} = 24\ \text{V}, V_{GS} = 0\ \text{V}, T_J = 125^\circ\text{C}$			250	
On-State Drain Current ^b	$I_{D(on)}$	$V_{DS} = 10\ \text{V}, V_{GS} = 10\ \text{V}$	60			A
Drain-Source On-State Resistance ^b	$r_{DS(on)}$	$V_{GS} = 10\ \text{V}, I_D = 30\ \text{A}$		0.007	0.010	Ω
		$V_{GS} = 5\ \text{V}, I_D = 30\ \text{A}$		0.010	0.015	
		$V_{GS} = 10\ \text{V}, I_D = 30\ \text{A}, T_J = 125^\circ\text{C}$		0.009	0.014	
Forward Transconductance ^b	g_{fs}	$V_{DS} = 15\ \text{V}, I_D = 30\ \text{A}$		45		S
Dynamic						
Input Capacitance	C_{iss}	$V_{GS} = 0\ \text{V}, V_{DS} = 25\ \text{V}, f = 1\ \text{MHz}$		2600		pF
Output Capacitance	C_{oss}			1500		
Reverse Transfer Capacitance	C_{rss}			750		
Total Gate Charge ^c	Q_g	$V_{DS} = 15\ \text{V}, V_{GS} = 10\ \text{V}, I_D = 60\ \text{A}$		100	120	nC
Gate-Source Charge ^c	Q_{gs}			10	15	
Gate-Drain Charge ^c	Q_{gd}			45	75	
Turn-On Delay Time ^c	$t_{d(on)}$	$V_{DD} = 30\ \text{V}, R_L = 1\ \Omega$ $I_D = 30\ \text{A}, V_{GEN} = 10\ \text{V}, R_G = 2.5\ \Omega$		14	30	ns
Rise Time ^c	t_r			25	50	
Turn-Off Delay Time ^c	$t_{d(off)}$			65	100	
Fall Time ^c	t_f			45	80	
Source-Drain Diode Ratings and Characteristics ($T_C = 25^\circ\text{C}$)						
Continuous Current	I_S				60	A
Pulsed Current	I_{SM}				240	
Forward Voltage ^b	V_{SD}	$I_F = 60\ \text{A}, V_{GS} = 0\ \text{V}$			1.6	V
Reverse Recovery Time	t_{rr}	$I_F = 60\ \text{A}, di_F/dt = 100\ \text{A}/\mu\text{s}$		160		ns
Peak Reverse Recovery Current	$I_{RM(REC)}$			13		A
Reverse Recovery Charge	Q_{rr}			1.0		μC

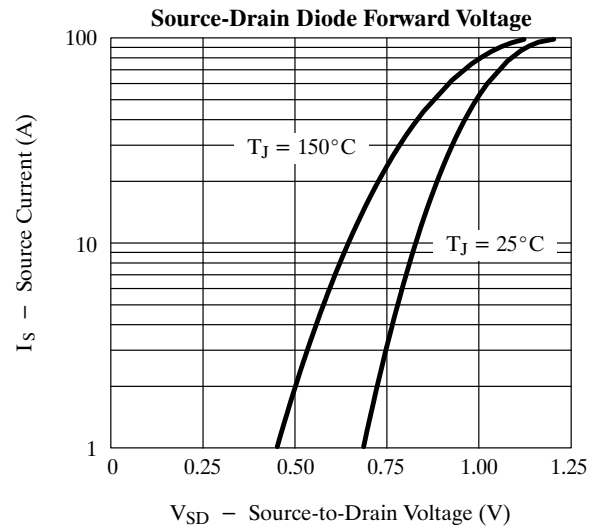
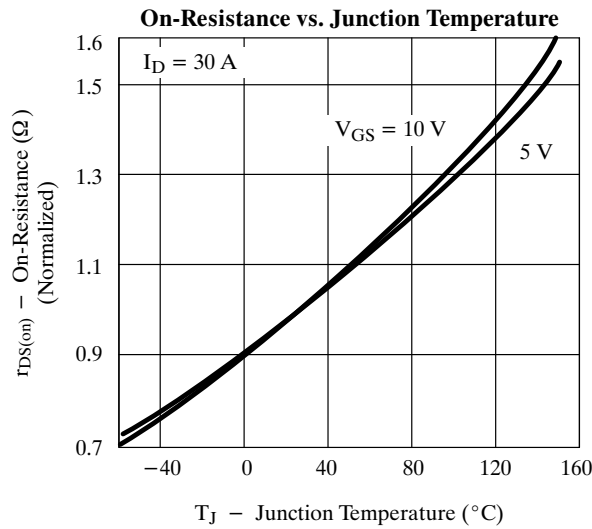
Notes:

- For design aid only; not subject to production testing.
- Pulse test; pulse width $\leq 300\ \mu\text{s}$, duty cycle $\leq 2\%$.
- Independent of operating temperature.

Typical Characteristics (25°C Unless Otherwise Noted)



Typical Characteristics (25°C Unless Otherwise Noted)



Thermal Ratings

